

Title (en)  
DEVICE FOR TESTING AND SORTING ELECTRONIC COMPONENTS

Publication  
**EP 0246672 B1 19900321 (DE)**

Application  
**EP 87110137 A 19841031**

Priority  
DE 3340183 A 19831107

Abstract (en)  
[origin: US4694964A] In a device for conveying components contained in an input magazine, particularly integrated chips, to an output magazine (3), which is connected to the input magazine by means of a testing device, individual component receiving portions (34) of the output magazine (3) are provided with storage and indicating devices (52), each of which store and indicate information corresponding to a component testing and measuring class. The components are supplied to the receiving portions (34) of the output magazine (3), on the basis of the data stored in the individual storage and indicating devices (52), so that a component determined by the testing device as belonging to a certain component test and measuring class is conveyed to the receiving portions (34) associated with this class, and in the absence of such a receiving portion is conveyed to a receiving portion which is still free, which is then marked as belonging to the test and measuring class in question.

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**B07C 5/344**; **B07C 5/36**

IPC 8 full level  
**B07C 5/344** (2006.01); **B07C 5/36** (2006.01)

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